L Number	Hits	Search Text	DB	Time stamp
-	3160	ring adj oscillator	USPAT	2004/10/07 13:48
-	2939	jtag "test access port" "1149.1" "scan chain"	USPAT	2004/10/07 13:52
-	9	(ring adj oscillator) same (jtag "test access port" "1149.1" "scan chain")	USPAT	2004/10/07 13:56
-	20	"speed binning"	USPAT	2004/10/07 13:59
-	38	(ring adj oscillator) with wafer	USPAT	2004/10/07 14:01
-	18	(jtag "test access port" "1149.1" "scan chain") with wafer	USPAT	2004/10/07 14:02
-	36	(ring adj oscillator) and tdi	USPAT	2004/10/07 15:42
-	10	(ring adj oscillator) same tdi	USPAT	2004/10/07 16:31
-	21384	process adj (parameter metric)	USPAT	2004/10/08 14:26
-	22242	process near2 variation	USPAT	2004/10/08 14:21
-	101	(process adj (parameter metric)) same oscillator	USPAT	2004/10/08 14:23
-	487	(process near2 variation) same oscillator	USPAT	2004/10/08 13:57
-	52	8.ab.	USPAT	2004/10/08 14:18
-	6	"6219813"	USPAT	2004/10/08 14:05
	12	5818250.URPN.	USPAT	2004/10/08 14:12
-	2	6463570.URPN.	USPAT	2004/10/08 14:17
-	22	8.cim.	USPAT	2004/10/08 14:18
-	450	(sensitive sensitiz\$3) near2 oscillator	USPAT	2004/10/08 14:24
	9	((sensitive sensitiz\$3) near2 oscillator) same ((process adj (parameter metric)) (process near2 variation))	USPAT	2004/10/08 14:25
-	1	((sensitive sensitiz\$3) near2 oscillator) same (wafer die dice)	USPAT	2004/10/08 14:30
-	1340	process adj (parameter metric variation)	EPO; JPO;	2004/10/08 14:26
		•	IBM_TDB	
-	25	(process adj (parameter metric variation)) same osciliator	EPO; JPO; IBM_TDB	2004/10/08 14:29
	16	test adj oscillator	EPO; JPO; IBM_TDB	2004/10/08 14:29
	175	test adj oscillator	USPAT	2004/10/08 14:30
	1	(test adj oscillator) same ((process adj (parameter metric)) (process near2 variation))	USPAT	2004/10/08 14:30
	2	(test adj oscillator) same (wafer die dice)	USPAT	2004/10/08 14:30
_	403	oscillator same (tdi tdo tms trst)	USPAT	2004/10/08 14:31
_	21	ring adj oscillator same (tdl tdo tms trst)	USPAT	2004/10/08 15:27
-	2	ring adj oscillator same (tdl tdo tms trst)	EPO; JPO; IBM_TDB	2004/10/08 14:32
-	82	oscillator same (tdl tdo tms trst)	EPO; JPO; iBM_TDB	2004/10/08 14:32
_	15	ring adj oscillator same (tck tclk)	USPAT	2004/10/08 14:34
-	7	ring adj oscillator same (jtag "test access port" "1149.1")	USPAT	2004/10/08 14:36
-	42	ring adj oscillator and (jtag "test access port" "1149.1")	USPAT	2004/10/08 15:42
-	29	ring adj oscillator same scan	USPAT	2004/10/08 14:46
-	201	ring adj oscillator same chain	USPAT	2004/10/08 15:09
-	25	46.clm.	USPAT	2004/10/08 14:51
-	148	ring adj oscillator with chain	USPAT	2004/10/08 14:51
-	14	46.ab.	USPAT	2004/10/08 14:51
	105	(enabl\$3 select\$3) near2 ring adj oscillator	USPAT	2004/10/08 15:12
-	425	(enabl\$3 select\$3) near2 ro	USPAT	2004/10/08 15:12
_	27	53.ab.	USPAT	2004/10/08 15:12
_	808	(enabl\$3 select\$3) near2 (test adj2 circuit)	USPAT	2004/10/08 15:41
•	45	((enabl\$3 select\$3) near2 (test adj2 circuit)) and (jtag "test access port" "1149.1")	USPAT	2004/10/08 16:54
-	9	((enabl\$3 select\$3) near2 (test adj2 circuit)) same (tdl tdo tms trst)	USPAT	2004/10/08 15:27
	63443	(enabl\$3 select\$3) near2 (test structure)	USPAT	2004/10/08 15:46
-	7	ring adj oscillator and "tap controller"	USPAT	2004/10/08 15:46
-	205	((enabi\$3 select\$3) near2 (test structure)) same "tap controller"	USPAT	2004/10/08 15:44
-	504	((enabi\$3 select\$3) near2 (test structure)) same (jtag "test access port" "1149.1")	USPAT	2004/10/08 15:45

•	4	67.ab.	USPAT	2004/10/08 15:46
-	27	ring adj oscillator same test adj structure	USPAT	2004/10/08 15:47
-	1204	"scan chain"	USPAT	2004/10/08 18:03
	152	"scan chain" with "shift register"	USPAT	2004/10/08 18:02
•	258	"shift register chain"	USPAT	2004/10/08 18:02
-	7	"shift register chain" with counter	USPAT	2004/10/08 18:03
•	38	"scan chain" with counter	USPAT	2004/10/08 18:13
	5	"scan chain" with oscillator	USPAT	2004/10/08 18:13
	14	"scan chain" same oscillator	USPAT	2004/10/12 10:23